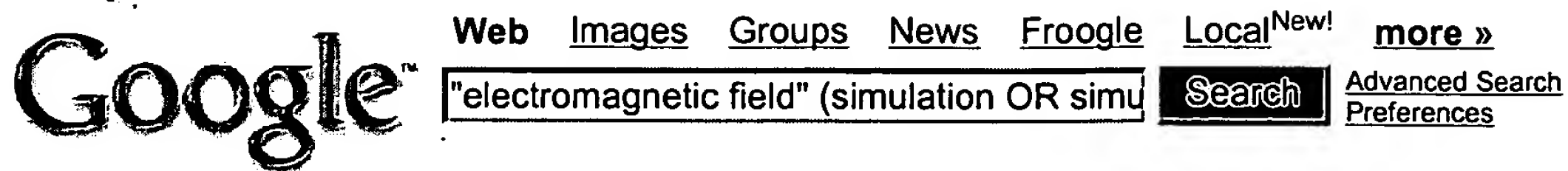


Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S2	771	((emf or (electro\$1magnetic adj field)) same simulat\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22
S3	4	S2 and ((statistic\$2 adj process) or (yield adj mange\$5) or (quality adj control\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 15:57
S4	4	S2 and ((statistic\$2 adj process) or (yield adj manag\$5) or (quality adj control\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:20
S5	464	(OKADO-TAKAHIRO KATO-HIDEYUKI ISHIHARA-JINSEI).in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22
S6	771	((emf or (electro\$1magnetic adj field)) same simulat\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22
S7	2	S5 and S6	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2005/03/24 17:22



Web Results 11 - 20 of about 189 for "electromagnetic field" (simulation OR simulating OR simulation) "st

Michael Yost Bibliography

... power frequency **electromagnetic field** exposures in the San Francisco Bay area.
... Hashmonay RA**, Yost MG., DB, Harris, EL, Thompson, Jr., "**Simulation** ...
depts.washington.edu/envhlth/about/facultypage/bibliography/bib_yost.html - 40k - [Cached](#) - [Similar pages](#)

Electrical Engineering Graduate Course Descriptions 421 - 729 ...

... Design **simulation** and verification. Heuristic techniques. CAD tools. ...
Selected advanced topics in **electromagnetic field** theory. ...
www.scu.edu/bulletin/engineering/elengrad_444-729.cfm - 31k - [Cached](#) - [Similar pages](#)
[[More results from www.scu.edu](#)]

MachineDesign.com: Wireless wonders for the factory

... for such purposes as **statistical process** control or quality assurance. ...
One **simulation** discovered that communications from the front of a fleet ...
www.machinedesign.com/ASP/strArticleID/56666/strSite/MDSite/viewSelectedArticle.asp - 60k -
[Cached](#) - [Similar pages](#)

[PDF] 5.1 Condition Monitoring and Fault Diagnosis of Electrical ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... a) **Electromagnetic field** monitoring, search coils, coils ... The **simulation**
results obtained through the models are also ...
ee.tamu.edu/~empelab/papers/ias'99-nandi%20review.pdf - [Similar pages](#)

FSU Undergraduate Bulletin 2000 - 2001

... parallel computing and communications **simulation** laboratories, and computer
... Prerequisite: EEL 3473. Applications of **electromagnetic field** theory. ...
registrar.fsu.edu/bulletin/archive/2000_2001/depts/electric_eng.htm - 35k - [Cached](#) - [Similar pages](#)

Purdue School of Engineering and Technology, IUPUI

... evaluation of design problems through **simulation** of systems described by ...
EE 604 **Electromagnetic Field** Theory (3) Class: 3 Lab: 0 Rec: 0 P: EE 311 or ...
www.engr.iupui.edu/bulletin/engprog.shtml - 55k - [Cached](#) - [Similar pages](#)

University of Manchester, School of Mathematics

... transport and assignment problems, **simulation** and Markov analysis. ... X-rays
or an **electromagnetic field** to an object, makes measurements on the ...
www.ma.umist.ac.uk/newmaths/undergrad/UMIST/Courseguides/G334.html - 81k - [Cached](#) - [Similar pages](#)

[PDF] Syllabus

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... enables students to apply tools of advanced modelling and **simulation** of systems.
Working on ... methods to solve complex **electromagnetic field** problems. ...
www.msc-ee.hs-bremen.de/internet/curriculum/MSc-EE-syllabi.pdf - [Similar pages](#)

[PDF] Acronyms Used in the 2003 Annual Progress Report

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... Catalytic Partial Oxidation. CPS. Chemical Process **Simulation**. cpsi. cells per
square inch ... **Electromagnetic Field**. EMI. Electromagnetic Interference ...
www.eere.energy.gov/hydrogenandfuelcells/pdfs/acronyms.pdf - [Similar pages](#)

FE Courses

... TNE073, **Electromagnetic Field** Theory and Electromagnetism, Igor Zozoulenko

... TNK077, Deterministic Modelling and **Simulation**, Anna Lombardi ...

www.itn.liu.se/english/education/areas/physics/courses.html - 21k - [Cached](#) - [Similar pages](#)

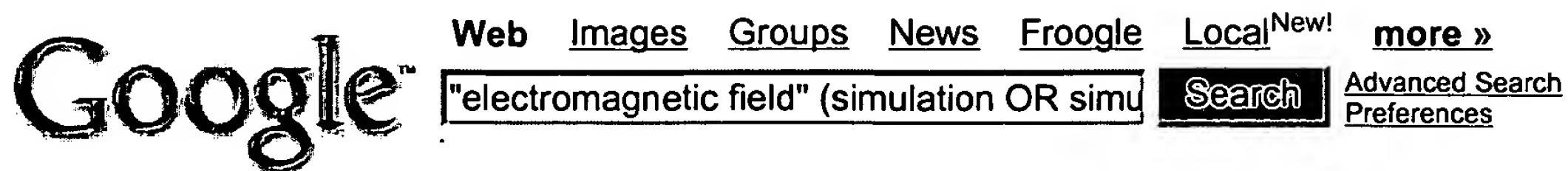
◀ Goooooooooooooogle ▶

Result Page: [Previous](#) [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [11](#) [Next](#)

[Search within results](#) | [Language Tools](#) | [Search Tips](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2005 Google



Web Results 11 - 20 of about 189 for "electromagnetic field" (simulation OR simulating OR simulation) "st

Michael Yost Bibliography

... power frequency **electromagnetic field** exposures in the San Francisco Bay area.
... Hashmonay RA***, Yost MG., DB, Harris, EL, Thompson, Jr., "**Simulation** ...
depts.washington.edu/envhlth/about/facultypage/bibliography/bib_yost.html - 40k - [Cached](#) - [Similar pages](#)

Electrical Engineering Graduate Course Descriptions 421 - 729 ...

... Design **simulation** and verification. Heuristic techniques. CAD tools. ...
Selected advanced topics in **electromagnetic field** theory. ...
www.scu.edu/bulletin/engineering/elengrad_444-729.cfm - 31k - [Cached](#) - [Similar pages](#)
[[More results from www.scu.edu](#)]

MachineDesign.com: Wireless wonders for the factory

... for such purposes as **statistical process** control or quality assurance. ...
One **simulation** discovered that communications from the front of a fleet ...
www.machinedesign.com/ASP/strArticleID/56666/strSite/MDSite/viewSelectedArticle.asp - 60k -
[Cached](#) - [Similar pages](#)

[PDF] 5.1 Condition Monitoring and Fault Diagnosis of Electrical ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... a) **Electromagnetic field** monitoring, search coils, coils ... The **simulation**
results obtained through the models are also ...
ee.tamu.edu/~empelab/papers/ias'99-nandi%20review.pdf - [Similar pages](#)

FSU Undergraduate Bulletin 2000 - 2001

... parallel computing and communications **simulation** laboratories, and computer
... Prerequisite: EEL 3473. Applications of **electromagnetic field** theory. ...
registrar.fsu.edu/bulletin/archive/2000_2001/depts/electric_eng.htm - 35k - [Cached](#) - [Similar pages](#)

Purdue School of Engineering and Technology, IUPUI

... evaluation of design problems through **simulation** of systems described by ...
EE 604 **Electromagnetic Field** Theory (3) Class: 3 Lab: 0 Rec: 0 P: EE 311 or ...
www.engr.iupui.edu/bulletin/engprog.shtml - 55k - [Cached](#) - [Similar pages](#)

University of Manchester, School of Mathematics

... transport and assignment problems, **simulation** and Markov analysis. ... X-rays
or an **electromagnetic field** to an object, makes measurements on the ...
www.ma.umist.ac.uk/newmaths/undergrad/UMIST/Courseguides/G334.html - 81k - [Cached](#) - [Similar pages](#)

[PDF] Syllabus

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... enables students to apply tools of advanced modelling and **simulation** of systems.
Working on ... methods to solve complex **electromagnetic field** problems. ...
www.msc-ee.hs-bremen.de/internet/curriculum/MSc-EE-syllabi.pdf - [Similar pages](#)

[PDF] Acronyms Used in the 2003 Annual Progress Report

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... Catalytic Partial Oxidation. CPS. Chemical Process **Simulation**. cpsi. cells per
square inch ... **Electromagnetic Field**. EMI. Electromagnetic Interference ...
www.eere.energy.gov/hydrogenandfuelcells/pdfs/acronyms.pdf - [Similar pages](#)

FE Courses

... TNE073, **Electromagnetic Field** Theory and Electromagnetism, Igor Zozoulenko

... TNK077, Deterministic Modelling and **Simulation**, Anna Lombardi ...

www.itn.liu.se/english/education/areas/physics/courses.html - 21k - [Cached](#) - [Similar pages](#)

◀ Goooooooooooooogle ▶

Result Page: [Previous](#) [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [11](#) [Next](#)

[Search within results](#) | [Language Tools](#) | [Search Tips](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2005 Google



[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#) [Local](#)^{New!} [more »](#)
"electromagnetic field" (simulation OR simu [Advanced Search](#)
[Preferences](#)

Web Results 1 - 10 of about 182 for "electromagnetic field" (simulation OR simulating OR simulation) "sta

Faculty of Electrical Engineering

... experimental work in the **electromagnetic field** and electric circuits. ...
focussed on novel algorithms, **simulation** procedures and expert systems towards ...
www.tuiasi.ro/pages/TUI97/eh97.htm - 49k - [Cached](#) - [Similar pages](#)

Courses

... heat transfer, fluid flow, and **electromagnetic field** problems. ... STELLA II
by High Performance Systems Inc., as a tool for system dynamics **simulation**. ...
www.eng.uwo.ca/gradstudies/Current%20Stud/Courses.htm - 61k - [Cached](#) - [Similar pages](#)

Analytical Mechanics: With an Introduction to Dynamical Systems

... should know? quantization of the **electromagnetic field**, relativistic one body
... approach to **simulation**. He guides readers through the use of **simulation** ...
www.yurinsha.com/318/p3.htm - 13k - [Cached](#) - [Similar pages](#)

Courses

... FP-472, Modeling & **Simulation** in Design of Hydraulic Components & Systems ...
GT-333, Inspection, Sampling and **Statistical Process** Control ...
www.msos.edu/eecs/cese/courses/courselist.php3 - 132k - [Cached](#) - [Similar pages](#)

Department of Electrical Engineering

... parallel computing and communications **simulation** laboratories, and computer
... Concepts and application of **statistical process** control are introduced. ...
registrar.fsu.edu/9899general/elect.html - 29k - [Cached](#) - [Similar pages](#)

Center For Professional Development

... MAE 498/598 Overview of Mechanical Engineering; IEE 498/598 Designed Experiments,
Statistical Process Control, ... CSE598: Modeling and **Simulation** ...
www.asuengineeringonline.com/online/?page=online_mp - 27k - [Cached](#) - [Similar pages](#)

Session LP1 - Poster Session VI.

... We've added **simulation** and analysis of axial angular momentum transport to our
... from the **electromagnetic field** quantities by field definition. ...
flux.aps.org/meetings/YR01/DPP01/abs/S1600.html - 187k - [Cached](#) - [Similar pages](#)

Instructors, CEI-Europe International Courses in Advanced Technology

... Training, **Statistical Process** Control and New Trends in Manufacturing. ...
Modeling Using **Electromagnetic Field Simulation**, published by Artech House. ...
www.cei.se/instructors.htm - 151k - [Cached](#) - [Similar pages](#)

Electrical Engineering Graduate Course Descriptions - 2003-2004 ...

... Time-varying **electromagnetic field** concepts starting with Maxwell's ...
Introduction to the algorithms used in a circuit **simulation** program like SPICE, ...
www.scu.edu/academic/bulletins/0304/engineering/elengrad.cfm - 61k - [Cached](#) - [Similar pages](#)

[PDF] 40 Inventive Principles in Quality Management

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... E. Use combined ultrasonic and **electromagnetic field** oscillations. ...

o Numerical **simulation** - virtual business development, strategic planning ...
www.triz-journal.com/archives/2003/03/a/01.pdf - [Similar pages](#)

Goooooooooooooogle ►

Result Page: 1 2 3 4 5 6 7 8 9 10 [Next](#)

Free! Google Desktop Search: Search your own computer. [Download now.](#)

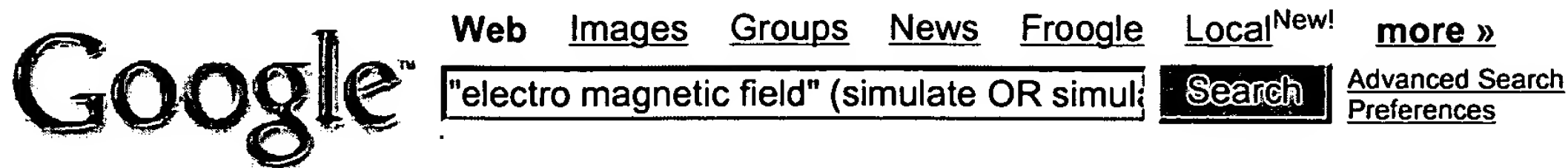
Find:  emails -  files -  chats -  web history -  media -  PDF

"electromagnetic field" (simulation) [Search](#)

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2005 Google



Web Results 1 - 6 of about 7 for "**electro magnetic field**" (**simulate** OR **simulating** OR **simulation**) "**statistic**

Did you mean: "**electromagnetic field**" (**simulation** OR simulating OR simulation) "**statistical process**"

Graduate Courses - Department of Mechanical Engineering

... thermal and fluid flow analysis, **electro-magnetic field** analysis and coupled
... corrosion and corrosion protection, **statistical process** control, ...

www.enme.umd.edu/graduate/courses/courses.html - 139k - [Cached](#) - [Similar pages](#)

[PDF] Graduate Handbook

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... such as stress analysis, thermal and fluid flow analysis, **electro-magnetic field**
... corrosion and corrosion protection, **statistical process** control, ...

www.enme.umd.edu/graduate/GraduateHandbook.pdf - [Similar pages](#)

Kevin Gao's Resume

... and **electro-magnetic field** analysis for electro-mechanical enclosures. ...
Implemented ISO9000 standard and **statistical process** control (SPC) method. ...

meltingpot.fortunecity.com/rwanda/243/resume.htm - 15k - [Cached](#) - [Similar pages](#)

[PDF] Tomography as a Metrology Technique for Semiconductor ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)

... led to the adoption of **Statistical Process** Control (SPC) [69] and Run-to- ...
At low pressures (1 mTorr - 1 Torr) an **electro-magnetic field** between the ...

bcam.berkeley.edu/ARCHIVE/theses/kruger_final.pdf - [Similar pages](#)

UM Testudo | Schedule Of Classes

... **Statistical process** control. Design team development. ... thermal and fluid
flow analysis, **electro-magnetic field** analysis and coupled boundary-value ...

www.sis.umd.edu/bin/soc?term=200501&crs=ENME - 63k - [Cached](#) - [Similar pages](#)

Dpt. of Defense SBIR Awards 1994

... to use this device to **simulate** the dolphin's ability to recognize objects.
... by a material changing its length when placed in **electro-magnetic field**. ...

www.nttc.edu/resources/funding/awards/dod/1994sbir/darpa94.asp - 513k - [Cached](#) - [Similar pages](#)

In order to show you the most relevant results, we have omitted some entries very similar to the 6 already displayed.

If you like, you can repeat the search with the omitted results included.

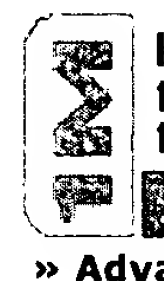
Did you mean to search for: "**electromagnetic field**" (**simulation** OR simulating OR simulation) "**statistical process**"

Free! Google Desktop Search: Search your own computer. [Download now.](#)

Find: emails - files - chats - web history - media - PDF

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**
[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

- 3) Limit the results by selecting Search Options.

- 4) Click Search. See [Search Examples](#)

```
((emf <or> (electro*magnetic
<near/1> field)) <and>
simulat*)<and> ((statistic*
<near/1> process*) <or>
```

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

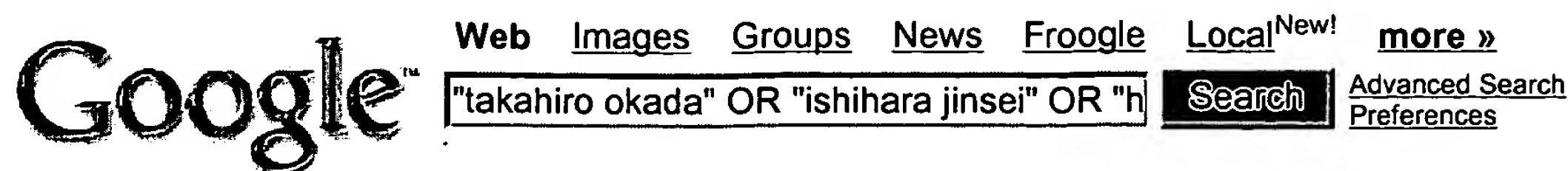
Search Options:**Select publication types:**

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:From year: to **Organize search results by:**Sort by: In: orderList Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved



Web Results 1 - 10 of about 337 for "takahiro okada" OR "ishihara jinsei" OR "hideyuki kato". (0.28 seconds)

Arcade History Database©

... Dead or Alive ++, 1998, Tecmo, CG director : **Hideyuki Kato**. Global Champion, 1994, Taito, Character designers : **Hideyuki Kato** ...
www.arcade-history.com/history_database.php?page=person&name=Hideyuki%20Kato - 15k -
[Cached](#) - [Similar pages](#)

[PDF] 研究業績リスト A 誌上発表 A1. Hideyuki Kato and Satoru Saito ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... **Hideyuki Kato**, I-Reduction and Twisted Conformal Field Theory, Int. J. Mod.
... Satoru Saito and **Hideyuki Kato**, From Soliton to String, ...
www.cns.nyu.edu/~cateau/pub.jap.pdf - [Similar pages](#)

N-Sider.com: Takahiro Okada

... **Takahiro Okada**. No Image. Company: Genius Sonority Position: Unknown Department: Unknown Entrance: Unknown. Notable Credits ...
www.n-sider.com/personnelview.php?personnelid=1350 - 7k - [Cached](#) - [Similar pages](#)

SF Kosmo

information. **hideyuki kato**. Home Treasure Features About Links. Contact, Gameography (incomplete). Gradius V ...BG Graphic Design.
www.classicgaming.com/sfkosmo/treasure/about/info/kato.html - 4k - [Cached](#) - [Similar pages](#)

A List of Published Papers

... Kazuhiro Miyauchi, Yushi Shirato, **Takahiro Okada**, Seiichiro Hangai, ...
Takahiro Okada, Fumihiko Hada, Masaaki Kasahara, Seiichiro Hangai, ...
www.seki.ee.kagu.sut.ac.jp/thesis/ronbun-e.html - 32k - [Cached](#) - [Similar pages](#)

Activity - [Translate this page]

... Yongcheng JIN, **Hideyuki KATO**, Inna R.KORABLOV, Koji IOKU and Nakamichi YAMASAKI, ...
... Yongcheng JIN, Inna KORBLOVA, **Hideyuki KATO** and Nakamichi YAMASAKI, ...
ehhttp.kankyotohoku.ac.jp/activity-j.html - 12k - Mar 24, 2005 - [Cached](#) - [Similar pages](#)

Executive Committee members

... Mr. **Takahiro OKADA** Instructed Olympic Medalists ... Mr. **Takahiro OKADA** Ms. Kaori YAMAGUCHI (Demonstration Games) Ms. Yoko SAKAUE Ms. Chiyori TATENO ...
before.ijf.org/general/gi-ec.html - 67k - Mar 22, 2005 - [Cached](#) - [Similar pages](#)

[PDF] Room Layout

File Format: PDF/Adobe Acrobat - [View as HTML](#)
... **Hideyuki KATO**. A343 Development of a Coating Reference Material for Thermo- ...
... Naofumi YAMADA (AIST) , **Hideyuki KATO** , . Tetsuya BABA ...
www.therm.shinshu-u.ac.jp/jstp25/program_e.pdf - [Similar pages](#)

[netbsd,01224] NetBSD on Color Classic II (Re: perl4 on NetBSD ... - [Translate this page]

... NetBSD ML,mail # 01223 , **Hideyuki Kato** <hideyuki@kato.totsuka.yokohama.jp> wrote: ひでゆき> 上記以外に正規リリースとは別のテスト用カーネル等が ひでゆき> ...
www.unixmagic.org/ml/netbsd/199703/msg00026.html - 4k - [Cached](#) - [Similar pages](#)

Anisotropic thermal-diffusivity measurements

... Hideyuki Kato et al 2001 Meas. Sci. Technol. 12 2074-2080 ... By author.

Hideyuki Kato, Tetsuya Baba, Masahiro Okaji. IOP CrossRef Search ...

www.iop.org/EJ/abstract/0957-0233/12/12/307 - [Similar pages](#)

Goooooooooooooogle ►

Result Page: 1 2 3 4 5 6 7 8 9 10 [Next](#)

Free! Google Desktop Search: Search your own computer. [Download now.](#)

Find:  emails -  files -  chats -  web history -  media -  PDF

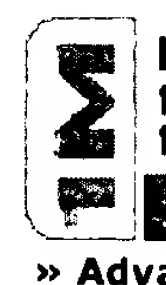
"takahiro okada" OR "ishihara jinsei" [Search](#)

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2005 Google

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

```
(okada <and> takahiro) <or>
(ishihara <and> jinsei) <or>
(hideyki <and> kato)
```

Start Search**Clear**

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:

Select publication types:

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:

 From year: **All** to **Present**

Organize search results by:

 Sort by: **Relevance**

 In: **Descending** order

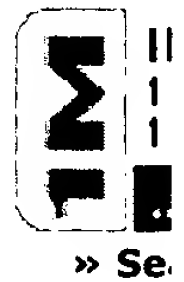
 List **15** Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
IEEE Xplore®
RELEASE 1.8

 Welcome
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

 Your search matched **0** of **1140634** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set

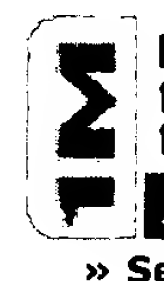
Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

Results:
No documents matched your query.
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
IEEE Xplore[®]
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore[®]

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

 Your search matched **2** of **1140634** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Real time and an in-process measuring system for the grinding process of cylindrical workpieces using Kalman filtering
Man Hyung lee; Jog Il Bae; Kang Sup Yoon; Harashima, F.;

 Industrial Electronics, IEEE Transactions on , Volume: 47 , Issue: 6 , Dec. 2000
 Pages:1326 - 1333

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) **IEEE JNL**
2 Development of real time and in-process gauging technology for grinding process of cylindrical workpieces
Jong-Nyun Lee; Jong Il Bae; Suk Lee; Jang Myung Lee;

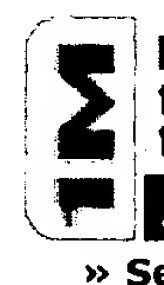
 Industrial Electronics, 1997. ISIE '97., Proceedings of the IEEE International Symposium on , Volume: 1 , 7-11 July 1997
 Pages:160 - 164 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(372 KB\)\]](#) **IEEE CNF**
Print Format
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
IEEE Xplore®
RELEASE 1.8

 Welcome
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **273** of **1140634** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 SPC implementation for improving product quality

Donnell, A.J.; Singhal, S.C.;

Electronics Manufacturing Technology Symposium, 1996., Nineteenth IEEE/CPMT , 14-16 Oct. 1996

Pages:416 - 421

[\[Abstract\]](#) [\[PDF Full-Text \(448 KB\)\]](#) IEEE CNF

2 Improving product quality in pulp mill using statistical process control (SPC)

Ho, T.; Henriksson, C.;

Electrical and Computer Engineering, 1993. Canadian Conference on , 14-17 Oct. 1993

Pages:953 - 957 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(292 KB\)\]](#) IEEE CNF

3 Statistical process control implementation for GaAs integrated circuit fabrication

Salzman, K.A.;

Gallium Arsenide Integrated Circuit (GaAs IC) Symposium, 1992. Technical Digest, 1992., 14th Annual IEEE , 4-7 Oct. 1992

Pages:217 - 220

[\[Abstract\]](#) [\[PDF Full-Text \(268 KB\)\]](#) IEEE CNF

4 Improving SPC in a wafer fabrication environment

Aston, D.;

Electronics Manufacturing Technology Symposium, 1998. Twenty-Third IEEE/CPMT , 19-21 Oct. 1998

Pages:346 - 351

[\[Abstract\]](#) [\[PDF Full-Text \(576 KB\)\]](#) IEEE CNF

5 A large-scale SPC implementation using the IBM multimedia SPC program

Harrison, M.; Shapiro, R.;

Advanced Semiconductor Manufacturing Conference and Workshop, 1992. ASI 92 Proceedings. IEEE/SEMI 1992 , 30 Sept.-1 Oct. 1992

Pages:153 - 158

[\[Abstract\]](#) [\[PDF Full-Text \(424 KB\)\]](#) IEEE CNF

6 Statistical process control for nonnormally distributed variables through the use of transformations

Cuellar, J.;

Advanced Semiconductor Manufacturing Conference and Workshop, 1991. ASI 91 Proceedings. IEEE/SEMI 1991 , 21-23 Oct. 1991

Pages:143 - 148

[\[Abstract\]](#) [\[PDF Full-Text \(356 KB\)\]](#) IEEE CNF

7 Non-standard application of SPC in sugar quality monitoring

Ooi, G.K.; McFarlane, D.C.;

Control '98. UKACC International Conference on (Conf. Publ. No. 455) , Volume 1 , 1-4 Sept. 1998

Pages:485 - 490 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(624 KB\)\]](#) IEE CNF

8 Statistical process control-the British Sugar experience

Sanigar, K.M.A.;

Applied Statistical Process Control, IEE Colloquium on , 12 Nov 1990

Pages:5/1 - 5/5

[\[Abstract\]](#) [\[PDF Full-Text \(216 KB\)\]](#) IEE CNF

9 SPC for visual rejects: a foundation for continuous improvement

Jernigan, T.; Sprague, K.;

Advanced Semiconductor Manufacturing Conference and Workshop, 1991. ASI 91 Proceedings. IEEE/SEMI 1991 , 21-23 Oct. 1991

Pages:153 - 157

[\[Abstract\]](#) [\[PDF Full-Text \(372 KB\)\]](#) IEEE CNF

10 Applying SPC to autonomic computing

Qian-Li Zhang; Ji Gao;

Machine Learning and Cybernetics, 2004. Proceedings of 2004 International Conference on , Volume: 2 , 26-29 Aug. 2004

Pages:744 - 749 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(704 KB\)\]](#) IEEE CNF

11

Making the six sigma leap using SPC data [quality]

Horst, R.L.;

Electronics Manufacturing Technology Symposium, 1999. Twenty-Fourth IEEE/CPMT , 18-19 Oct. 1999

Pages:50 - 53

[\[Abstract\]](#)

[\[PDF Full-Text \(304 KB\)\]](#)

IEEE CNF

12

Using transformations to analyze defect structure SPC charts: a case study

Mojzak, G.;

Advanced Semiconductor Manufacturing Conference and Workshop, 1991. ASI 91 Proceedings. IEEE/SEMI 1991 , 21-23 Oct. 1991

Pages:149 - 152

[\[Abstract\]](#)

[\[PDF Full-Text \(256 KB\)\]](#)

IEEE CNF

13

A manufacturing driven `real-time statistical process control' implementation model

Hunt, S.J.;

Semiconductor Manufacturing Science Symposium, 1989. ISMSS 1989., IEEE/International , 22-24 May 1989

Pages:41 - 45

[\[Abstract\]](#)

[\[PDF Full-Text \(500 KB\)\]](#)

IEEE CNF

14

Statistical process control in software quality assurance

Demmy, W.S.; Petrini, A.B.;

Aerospace and Electronics Conference, 1989. NAECON 1989., Proceedings of the IEEE 1989 National , 22-26 May 1989

Pages:1585 - 1590 vol.4

[\[Abstract\]](#)

[\[PDF Full-Text \(392 KB\)\]](#)

IEEE CNF

15

SPC application in the chemical industry

Gallagher, W.M.;

Applied Statistical Process Control, IEE Colloquium on , 12 Nov 1990

Pages:4/1 - 4/2

[\[Abstract\]](#)

[\[PDF Full-Text \(48 KB\)\]](#)

IEE CNF

1

2

3

4

5

6

7

8

9

10

11

12

13

14

15

16

17

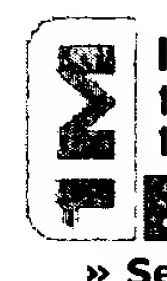
18

19

Next

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)
IEEE Xplore®
RELEASE 1.8

 Welcome
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **273** of **1140634** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

☒ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

16 Run by run process control: combining SPC and feedback control

Sachs, E.; Hu, A.; Ingolfsson, A.;

Semiconductor Manufacturing, IEEE Transactions on , Volume: 8 , Issue: 1 , F 1995

Pages:26 - 43

[\[Abstract\]](#) [\[PDF Full-Text \(1528 KB\)\]](#) **IEEE JNL**

17 The mathematics of success and failure [SPC]

Rose, K.;

Circuits and Devices Magazine, IEEE , Volume: 7 , Issue: 6 , Nov. 1991

Pages:26 - 30

[\[Abstract\]](#) [\[PDF Full-Text \(392 KB\)\]](#) **IEEE JNL**

18 EPIS (equipment and process information system) a new prospect EDA and SPC system

Chou, C.; Yang, K.; Chiang, G.; Shiao, R.;

Semiconductor Manufacturing Technology Workshop, 1998 , 16-17 June 1998

Pages:163 - 166

[\[Abstract\]](#) [\[PDF Full-Text \(356 KB\)\]](#) **IEEE CNF**

19 SPC for magnet wire

Greene, T.;

Electrical Electronics Insulation Conference and Electrical Manufacturing & Coil Winding Conference, 1993. Proceedings., Chicago '93 EEIC/ICWA Exposition , Oct. 1993

Pages:493 - 494

[\[Abstract\]](#) [\[PDF Full-Text \(184 KB\)\]](#) IEEE CNF

20 Implementing SPC in a large manufacturing facility: an example

Kanthanathan, M.; Wheeler, S.;

Electronic Manufacturing Technology Symposium, 1990 Proceedings, 'Competi
Manufacturing for the Next Decade'. IEMT Symposium, Ninth IEEE/CHMT
International , 1-3 Oct. 1990
Pages:200 - 203

[\[Abstract\]](#) [\[PDF Full-Text \(240 KB\)\]](#) IEEE CNF

21 SPC in short run processes

Nugent, B.A.;

Aerospace and Electronics Conference, 1990. NAECON 1990., Proceedings of t
IEEE 1990 National , 21-25 May 1990
Pages:1304 - 1307 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(228 KB\)\]](#) IEEE CNF

22 Fault detection in an overheads condenser using multivariate SPC

Wilson, D.J.H.; Irwin, G.W.; Lightbody, G.;

Modeling and Signal Processing for Fault Diagnosis (Digest No: 1996/260), IEI
Colloquium on , 18 Sept. 1996
Pages:7/1 - 7/6

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) IEE CNF

23 Experiences of introducing SPC in a confectionery factory

Bidder, P.L.;

Applied Statistical Process Control, IEE Colloquium on , 12 Nov 1990
Pages:2/1 - 2/2

[\[Abstract\]](#) [\[PDF Full-Text \(72 KB\)\]](#) IEE CNF

24 Personal computer based statistical process control (PC-SPC) in a manufacturing environment

Basarab-Horwath, I.; Dickinson, M.;

Use of Personal Computer Systems for Plant Monitoring and Control, IEE
Colloquium on , 23 Mar 1989
Pages:5/1 - 5/3

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) IEE CNF

25 Statistical process control in semiconductor manufacturing

Spanos, C.J.;

Proceedings of the IEEE , Volume: 80 , Issue: 6 , June 1992
Pages:819 - 830

[\[Abstract\]](#) [\[PDF Full-Text \(988 KB\)\]](#) IEEE JNL

26 Statistical process control application to weld process

Cook, G.E.; Maxwell, J.E.; Barnett, R.J.; Strauss, A.M.;

Industry Applications, IEEE Transactions on , Volume: 33 , Issue: 2 , March-A

1997
Pages:454 - 463

[\[Abstract\]](#) [\[PDF Full-Text \(248 KB\)\]](#) IEEE JNL

27 An effective SPC approach to monitoring semiconductor quality data with multiple variation sources

Argon Chen; Ruey-Shan Guo; Pei-Chen Yeh;

Semiconductor Manufacturing Technology Workshop, 2000 , 14-15 June 2000

Pages:279 - 282

[\[Abstract\]](#) [\[PDF Full-Text \(212 KB\)\]](#) IEEE CNF

28 The impact of lot-to-lot and wafer-to-wafer variations on SPC

Nurani, R.K.; Shanthikumar, J.G.;

Statistical Metrology, 1997 2nd International Workshop on , 8 June 1997

Pages:110 - 112

[\[Abstract\]](#) [\[PDF Full-Text \(168 KB\)\]](#) IEEE CNF

29 Microelectronics process engineering program at SJSU

Parent, D.; Dessouky, Y.; Gleixner, S.; Young, G.; Allen, E.;

University/Government/Industry Microelectronics Symposium, 2001. Proceedings of the Fourteenth Biennial , 17-20 June 2001

Pages:128 - 134

[\[Abstract\]](#) [\[PDF Full-Text \(352 KB\)\]](#) IEEE CNF

30 Optimization of inspection strategies by use of quality cost models SPC

Oppermann, M.; Sauer, W.; Wohlrabe, H.;

Electronics Technology: Concurrent Engineering in Electronic Packaging, 2001 24th International Spring Seminar on , 5-9 May 2001

Pages:293 - 297

[\[Abstract\]](#) [\[PDF Full-Text \(352 KB\)\]](#) IEEE CNF

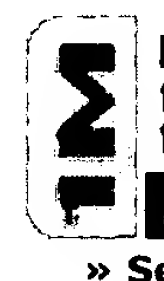
[Prev](#) [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [11](#) [12](#) [13](#) [14](#) [15](#) [16](#) [17](#) [18](#) [19](#) [Next](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#)
[Publications/Services](#)
[Standards](#)
[Conferences](#)
[Careers/Jobs](#)
IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

[Help](#)
[FAQ](#)
[Terms](#)
[IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **10** of **1140634** documents.
 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☒ Check to search within this result set
Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard
1 Statistical process control application to weld process
Cook, G.E.; Maxwell, J.E.; Barnett, R.J.; Strauss, A.M.;

Industry Applications, IEEE Transactions on , Volume: 33 , Issue: 2 , March-A 1997

Pages:454 - 463

[\[Abstract\]](#) [\[PDF Full-Text \(248 KB\)\]](#) IEEE JNL
2 Hierarchical process control by combining SPC and soft computing methods
Wonoh Kim; Vachtsevanos, G.;

Fuzzy Information Processing Society, 2000. NAFIPS. 19th International Conference of the North American , 13-15 July 2000

Pages:485 - 489

[\[Abstract\]](#) [\[PDF Full-Text \(500 KB\)\]](#) IEEE CNF
3 Fuzzy supervision in statistical process control
Zalila, Z.; Fatene, M.; Kadhi, R.;

Systems, Man, and Cybernetics, 1998. 1998 IEEE International Conference on , Volume: 1 , 11-14 Oct 1998

Pages:638 - 643 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(536 KB\)\]](#) IEEE CNF
4 On-line diagnostic monitoring of photoresist ashing
Stefani, J.; Loewenstein, L.M.; Sullivan, M.;

Semiconductor Manufacturing, IEEE Transactions on , Volume: 8 , Issue: 1 , F 1995

Pages:2 - 9

[\[Abstract\]](#) [\[PDF Full-Text \(672 KB\)\]](#) IEEE JNL

5 Defects tail off with six-sigma manufacturing

Fieler, P.E.; Loverro, N., Jr.;

Circuits and Devices Magazine, IEEE , Volume: 7 , Issue: 5 , Sept. 1991

Pages:18 - 20, 48

[\[Abstract\]](#) [\[PDF Full-Text \(356 KB\)\]](#) IEEE JNL

6 On board statistical process control on the NV-GSD series ion implan

Sedgewick, J.E.; Franceschelli, A.J.; Hazelton, J.; Malenfant, J.;

Ion Implantation Technology. Proceedings of the 11th International Conferenc
on , 16-21 June 1996

Pages:501 - 504

[\[Abstract\]](#) [\[PDF Full-Text \(480 KB\)\]](#) IEEE CNF

**7 A fuzzy expert system for fault detection in statistical process contr
industrial processes**

El-Shal, S.M.; Morris, A.S.;

Systems, Man and Cybernetics, Part C, IEEE Transactions on , Volume: 30 , Is
2 , May 2000

Pages:281 - 289

[\[Abstract\]](#) [\[PDF Full-Text \(236 KB\)\]](#) IEEE JNL

**8 A practical statistical technique to improve seal integrity and reliabi
of microelectronic packages**

Narasimhan, T.R.; Trotter, E.H.;

Integrated Reliability Workshop Final Report, 1997 IEEE International , 13-16
1997

Pages:126 - 127

[\[Abstract\]](#) [\[PDF Full-Text \(180 KB\)\]](#) IEEE CNF

9 Multivariate statistics and neural networks in process fault detection

Martin, E.B.; Morris, A.J.;

Qualitative and Quantitative Modelling Methods for Fault Diagnosis, IEE Colloq
on , 24 Apr 1995

Pages:7/1 - 7/8

[\[Abstract\]](#) [\[PDF Full-Text \(496 KB\)\]](#) IEE CNF

**10 Shallow trench isolation run-to-run control project at Infineon
Technologies Richmond**

Jowett, P.; Morozov, V.;

Advanced Semiconductor Manufacturing 2002 IEEE/SEMI Conference and
Workshop , 30 April-2 May 2002

Pages:107 - 112

[\[Abstract\]](#) [\[PDF Full-Text \(557 KB\)\]](#) IEEE CNF

[New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved